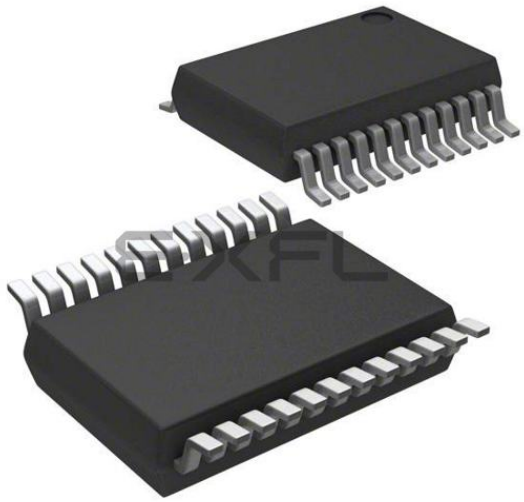
Silicon Labs - EFM8LB11F32E-A-QSOP24 Datasheet



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"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Discontinued at Digi-Key
Core Processor	CIP-51 8051
Core Size	8-Bit
Speed	72MHz
Connectivity	I²C, SMBus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, POR, PWM, WDT
Number of I/O	21
Program Memory Size	32KB (32K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	2.25K x 8
Voltage - Supply (Vcc/Vdd)	2.2V ~ 3.6V
Data Converters	A/D 13x14b; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	24-SSOP (0.154", 3.90mm Width)
Supplier Device Package	24-QSOP
Purchase URL	https://www.e-xfl.com/product-detail/silicon-labs/efm8lb11f32e-a-qsop24

Ordering Part Number	Flash Memory (kB)	RAM (Bytes)	Digital Port I/Os (Total)	ADC0 Channels	Voltage DACs	Comparator 0 Inputs	Comparator 1 Inputs	Pb-free (RoHS Compliant)	Temperature Range	Package
EFM8LB12F32E-A-QFN32	32	2304	29	20	4	10	9	Yes	-40 to +105 °C	QFN32
EFM8LB12F32E-A-QFP32	32	2304	28	20	4	10	9	Yes	-40 to +105 °C	QFP32
EFM8LB12F32E-A-QFN24	32	2304	20	12	4	6	6	Yes	-40 to +105 °C	QFN24
EFM8LB12F32E-A-QSOP24	32	2304	21	13	4	6	7	Yes	-40 to +105 °C	QSOP24
EFM8LB11F32E-A-QFN32	32	2304	29	20	2	10	9	Yes	-40 to +105 °C	QFN32
EFM8LB11F32E-A-QFP32	32	2304	28	20	2	10	9	Yes	-40 to +105 °C	QFP32
EFM8LB11F32E-A-QFN24	32	2304	20	12	2	6	6	Yes	-40 to +105 °C	QFN24
EFM8LB11F32E-A-QSOP24	32	2304	21	13	2	6	7	Yes	-40 to +105 °C	QSOP24
EFM8LB11F16E-A-QFN32	16	1280	29	20	2	10	9	Yes	-40 to +105 °C	QFN32
EFM8LB11F16E-A-QFP32	16	1280	28	20	2	10	9	Yes	-40 to +105 °C	QFP32
EFM8LB11F16E-A-QFN24	16	1280	20	12	2	6	6	Yes	-40 to +105 °C	QFN24
EFM8LB11F16E-A-QSOP24	16	1280	21	13	2	6	7	Yes	-40 to +105 °C	QSOP24
EFM8LB10F16E-A-QFN32	16	1280	29	20	0	10	9	Yes	-40 to +105 °C	QFN32
EFM8LB10F16E-A-QFP32	16	1280	28	20	0	10	9	Yes	-40 to +105 °C	QFP32
EFM8LB10F16E-A-QFN24	16	1280	20	12	0	6	6	Yes	-40 to +105 °C	QFN24
EFM8LB10F16E-A-QSOP24	16	1280	21	13	0	6	7	Yes	-40 to +105 °C	QSOP24

3.7 Analog

14/12/10-Bit Analog-to-Digital Converter (ADC0)

The ADC is a successive-approximation-register (SAR) ADC with 14-, 12-, and 10-bit modes, integrated track-and hold and a programmable window detector. The ADC is fully configurable under software control via several registers. The ADC may be configured to measure different signals using the analog multiplexer. The voltage reference for the ADC is selectable between internal and external reference sources.

- Up to 20 external inputs
- Single-ended 14-bit, 12-bit and 10-bit modes
- Supports an output update rate of up to 1 Msps in 12-bit mode
- Channel sequencer logic with direct-to-XDATA output transfers
- Operation in a low power mode at lower conversion speeds
- Asynchronous hardware conversion trigger, selectable between software, external I/O and internal timer and configurable logic sources
- Output data window comparator allows automatic range checking
- Support for output data accumulation
- Conversion complete and window compare interrupts supported
- Flexible output data formatting
- Includes a fully-internal fast-settling 1.65 V reference and an on-chip precision 2.4 / 1.2 V reference, with support for using the supply as the reference, an external reference and signal ground
- Integrated factory-calibrated temperature sensor

12-Bit Digital-to-Analog Converters (DAC0, DAC1, DAC2, DAC3)

The DAC modules are 12-bit Digital-to-Analog Converters with the capability to synchronize multiple outputs together. The DACs are fully configurable under software control. The voltage reference for the DACs is selectable between internal and external reference sources.

- Voltage output with 12-bit performance
- Hardware conversion trigger, selectable between software, external I/O and internal timer and configurable logic sources
- Outputs may be configured to persist through reset and maintain output state to avoid system disruption
- Multiple DAC outputs can be synchronized together
- DAC pairs (DAC0 and 1 or DAC2 and 3) support complementary output waveform generation
- Outputs may be switched between two levels according to state of configurable logic / PWM input trigger
- Flexible input data formatting
- Supports references from internal supply, on-chip precision reference, or external VREF pin

Low Current Comparators (CMP0, CMP1)

An analog comparator is used to compare the voltage of two analog inputs, with a digital output indicating which input voltage is higher. External input connections to device I/O pins and internal connections are available through separate multiplexers on the positive and negative inputs. Hysteresis, response time, and current consumption may be programmed to suit the specific needs of the application.

The comparator includes the following features:

- Up to 10 (CMP0) or 9 (CMP1) external positive inputs
- Up to 10 (CMP0) or 9 (CMP1) external negative inputs
- Additional input options:
  - Internal connection to LDO output
  - Direct connection to GND
  - Direct connection to VDD
  - Dedicated 6-bit reference DAC
- Synchronous and asynchronous outputs can be routed to pins via crossbar
- Programmable hysteresis between 0 and ±20 mV
- Programmable response time
- Interrupts generated on rising, falling, or both edges
- PWM output kill feature

4.1.12 DACs

Table 4.12. DACs

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Resolution	N_{bits}			12		Bits
Throughput Rate	f_S		—	—	200	ksps
Integral Nonlinearity	INL		TBD	±0.5	TBD	LSB
Differential Nonlinearity	DNL		TBD	±5	TBD	LSB
Output Noise	VREF = 2.4 V f_S = 0.1 Hz to 300 kHz		—	110	—	μV_{RMS}
Slew Rate	SLEW		—	±1	—	V/µs
Output Settling Time to 1 LSB	t_{SETTLE}	V_{OUT} change between 25% and 75% Full Scale	—	2.6	5	µs
Power-on Time	t_{PWR}		—	—	10	µs
Voltage Reference Range	V_{REF}		1.15	—	V_{DD}	V
Power Supply Rejection Ratio	PSRR	DC, V_{OUT} = 50% Full Scale	—	110	—	dB
		1 kHz, V_{OUT} = 50% Full Scale	—	60	—	dB
Total Harmonic Distortion	THD	V_{OUT} = 10 kHz sine wave, 10% to 90%	60	—	—	dB
Offset Error	E_{OFF}	VREF = 2.4 V	TBD	±0.5	TBD	LSB
Offset Temperature Coefficient	TC_{OFF}		—	TBD	—	ppm/°C
Full-Scale Error	E_{FS}	VREF = 2.4 V	TBD	±5	TBD	LSB
Full-Scale Error Tempco	TC_{FS}		—	TBD	—	ppm/°C
External Load Impedance	R_{LOAD}		2	—	—	kΩ
External Load Capacitance	C_{LOAD}		TBD	—	100	pF
Load Regulation		V_{OUT} = 50% Full Scale I_{OUT} = -2 to 2 mA	—	100	TBD	µV/mA

4.2 Thermal Conditions

Table 4.16. Thermal Conditions

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Thermal Resistance	θ_{JA}	QFN24 Packages	—	TBD	—	°C/W
		QFN32 Packages	—	TBD	—	°C/W
		QFP32 Packages	—	80	—	°C/W
		QSOP24 Packages	—	65	—	°C/W

Note:
1. Thermal resistance assumes a multi-layer PCB with any exposed pad soldered to a PCB pad.

4.3 Absolute Maximum Ratings

Stresses above those listed in Table 4.17 Absolute Maximum Ratings on page 27 may cause permanent damage to the device. This is a stress rating only and functional operation of the devices at those or any other conditions above those indicated in the operation listings of this specification is not implied. Exposure to maximum rating conditions for extended periods may affect device reliability. For more information on the available quality and reliability data, see the Quality and Reliability Monitor Report at http://www.silabs.com/support/quality/pages/default.aspx.

Table 4.17. Absolute Maximum Ratings

Parameter	Symbol	Test Condition	Min	Max	Unit
Ambient Temperature Under Bias	T_{BIAS}		-55	125	°C
Storage Temperature	T_{STG}		-65	150	°C
Voltage on VDD	V_{DD}		GND-0.3	4.2	V
Voltage on VIO[2]	V_{IO}		GND-0.3	V_{DD}+0.3	V
Voltage on I/O pins or RSTb, excluding P2.0-P2.3 (QFN24 and QSOP24) or P3.0-P3.3 (QFN32 and QFP32)	V_{IN}	V_{IO} > TBD V	GND-0.3	TBD	V
		V_{IO} < TBD V	GND-0.3	TBD	V
Voltage on P2.0-P2.3 (QFN24 and QSOP24) or P3.0-P3.3 (QFN32 and QFP32)	V_{IN}		GND-0.3	V_{DD}+0.3	V
Total Current Sunk into Supply Pin	I_{VDD}		—	400	mA
Total Current Sourced out of Ground Pin	I_{GND}		400	—	mA
Current Sourced or Sunk by any I/O Pin or RSTb	I_{IO}		-100	100	mA

Note:
1. Exposure to maximum rating conditions for extended periods may affect device reliability.
2. In certain package configurations, the VIO and VDD supplies are bonded to the same pin.

5. Typical Connection Diagrams

5.1 Power

Figure 5.1 Power Connection Diagram on page 28 shows a typical connection diagram for the power pins of the device.

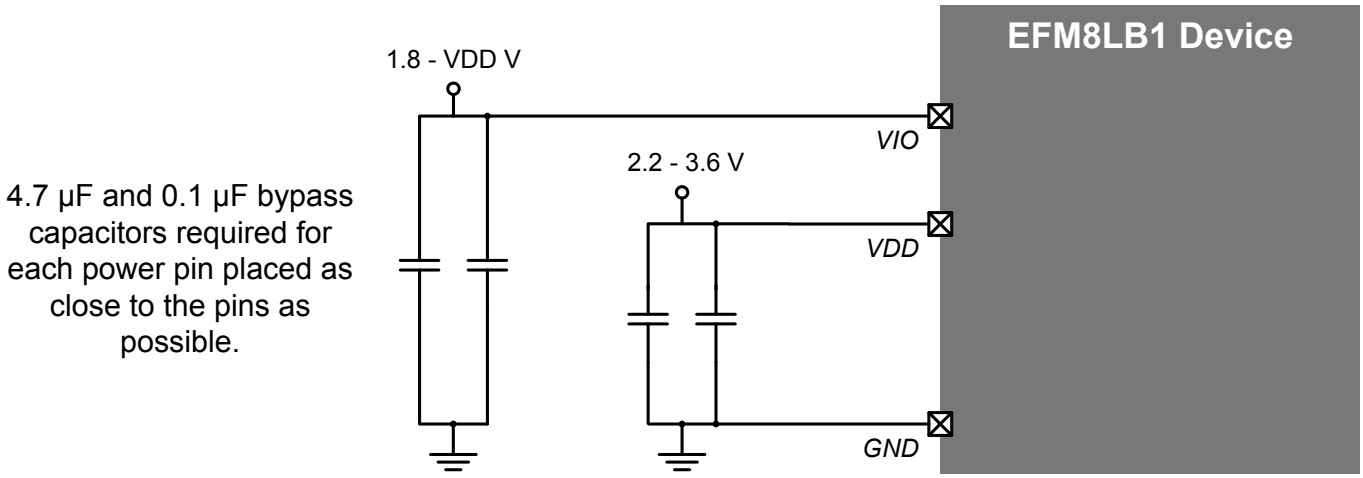

Figure 5.1. Power Connection Diagram

5.2 Debug

The diagram below shows a typical connection diagram for the debug connections pins. The pin sharing resistors are only required if the functionality on the C2D (a GPIO pin) and the C2CK (RSTb) is routed to external circuitry. For example, if the RSTb pin is connected to an external switch with debouncing filter or if the GPIO sharing with the C2D pin is connected to an external circuit, the pin sharing resistors and connections to the debug adapter must be placed on the hardware. Otherwise, these components and connections can be omitted.

For more information on debug connections, see the example schematics and information available in AN127: "Pin Sharing Techniques for the C2 Interface." Application notes can be found on the Silicon Labs website (http://www.silabs.com/8bit-appnotes) or in Simplicity Studio.

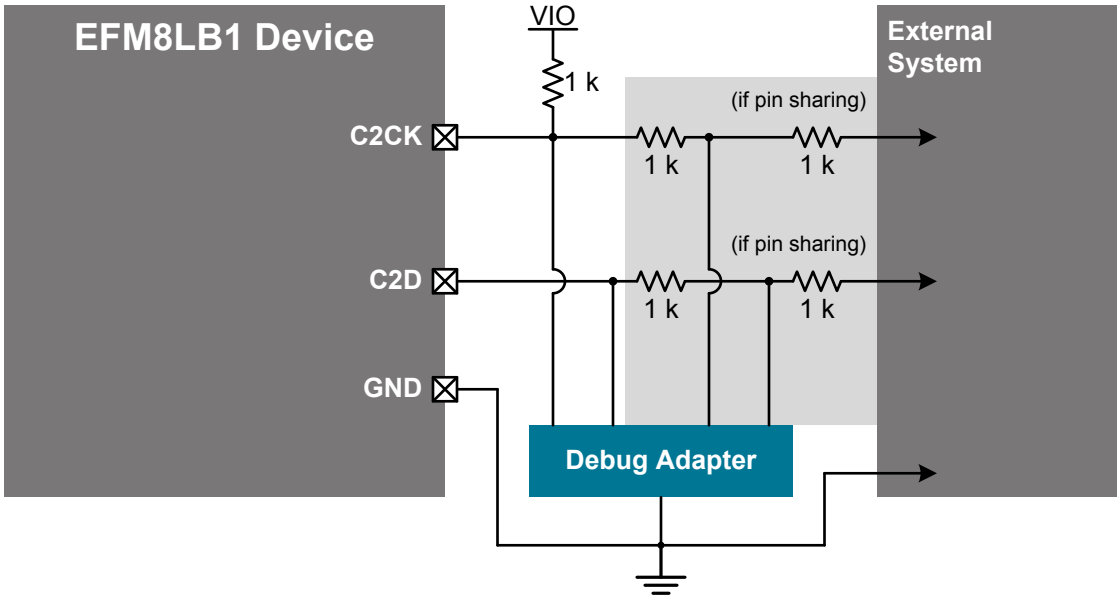

Figure 5.2. Debug Connection Diagram

5.3 Other Connections

Other components or connections may be required to meet the system-level requirements. Application Note AN203: "8-bit MCU Printed Circuit Board Design Notes" contains detailed information on these connections. Application Notes can be accessed on the Silicon Labs website (www.silabs.com/8bit-appnotes).

6.2 EFM8LB1x-QFP32 Pin Definitions

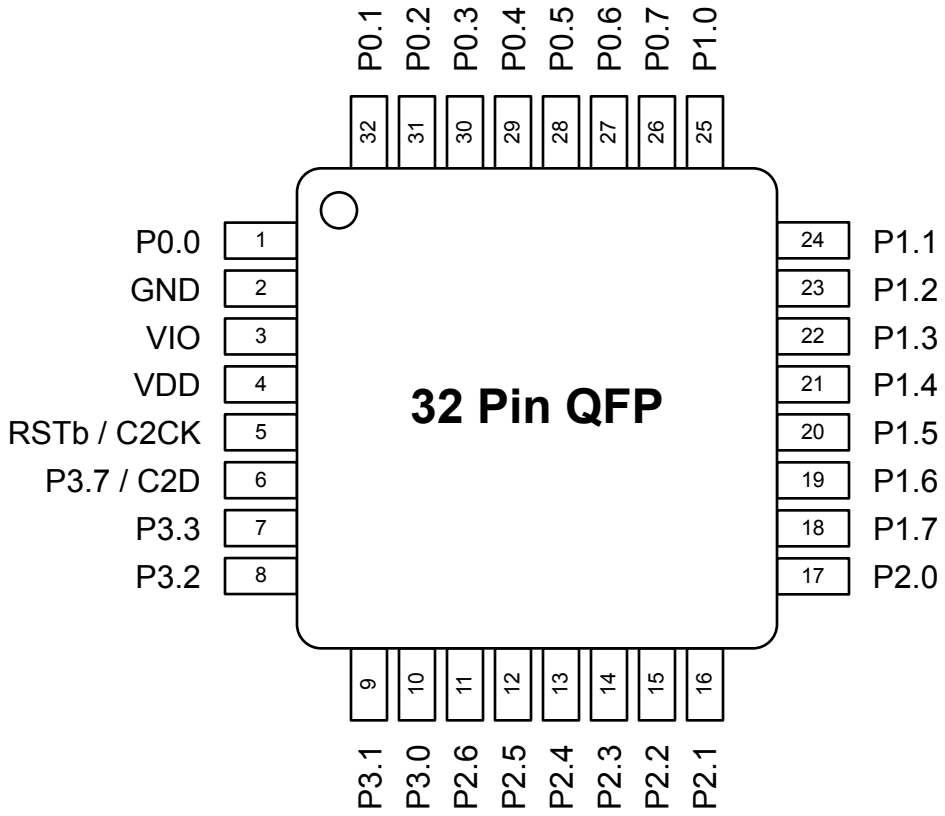

Figure 6.2. EFM8LB1x-QFP32 Pinout

Table 6.2. Pin Definitions for EFM8LB1x-QFP32

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
1	P0.0	Multifunction I/O	Yes	P0MAT.0 INT0.0 INT1.0 CLU0A.8 CLU2A.8 CLU3B.8	VREF
2	GND	Ground			
3	VIO	I/O Supply Power Input			
4	VDD	Supply Power Input			
5	RSTb / C2CK	Active-low Reset / C2 Debug Clock			

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
18	P1.7	Multifunction I/O	Yes	P1MAT.7 CLU0B.15 CLU1B.13 CLU2A.13	ADC0.13 CMP0P.9 CMP0N.9
19	P1.6	Multifunction I/O	Yes	P1MAT.6 CLU0A.15 CLU1B.12 CLU2A.12	ADC0.12
20	P1.5	Multifunction I/O	Yes	P1MAT.5 CLU0B.14 CLU1A.13 CLU2B.13 CLU3B.11	ADC0.11
21	P1.4	Multifunction I/O	Yes	P1MAT.4 CLU0A.14 CLU1A.12 CLU2B.12 CLU3B.10	ADC0.10
22	P1.3	Multifunction I/O	Yes	P1MAT.3 CLU0B.13 CLU1B.11 CLU2B.11 CLU3A.13	ADC0.9
23	P1.2	Multifunction I/O	Yes	P1MAT.2 CLU0A.13 CLU1A.11 CLU2B.10 CLU3A.12 CLU3B.13	ADC0.8 CMP0P.8 CMP0N.8
24	P1.1	Multifunction I/O	Yes	P1MAT.1 CLU0B.12 CLU1B.10 CLU2A.11 CLU3B.12	ADC0.7 CMP0P.7 CMP0N.7

6.3 EFM8LB1x-QFN24 Pin Definitions

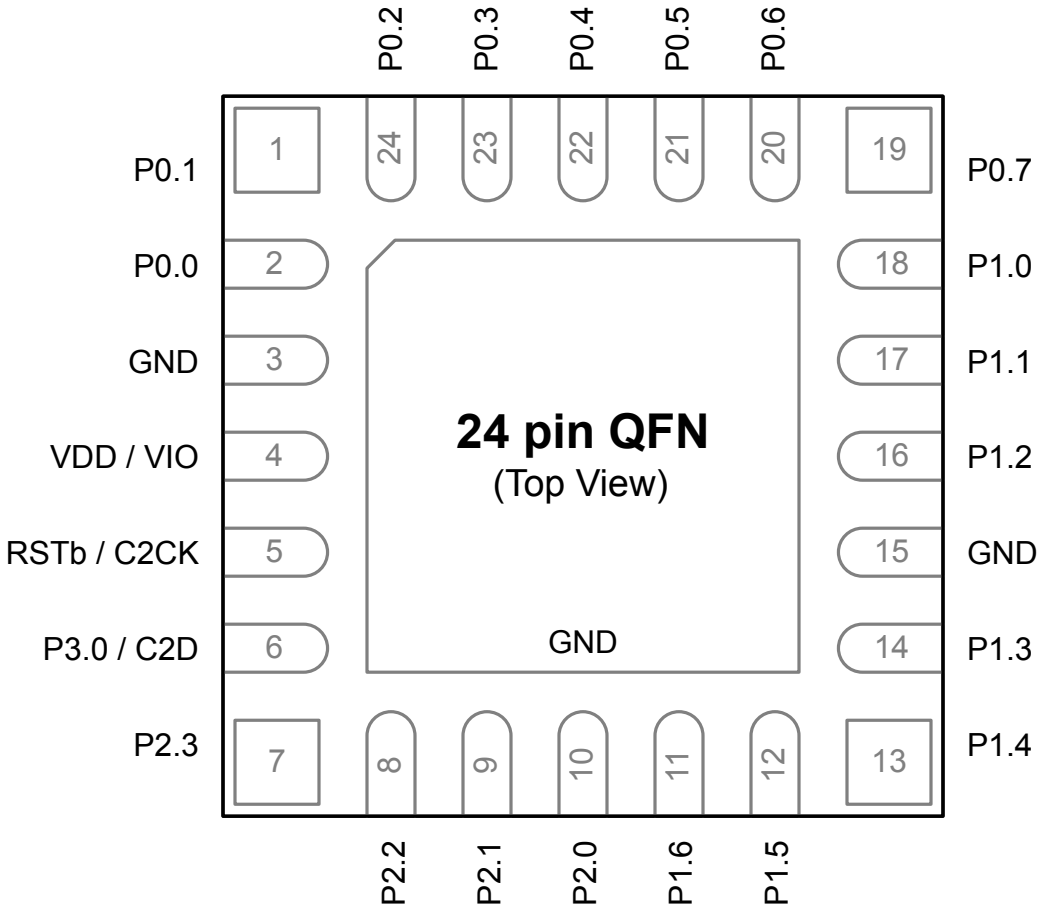

Figure 6.3. EFM8LB1x-QFN24 Pinout

Table 6.3. Pin Definitions for EFM8LB1x-QFN24

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
1	P0.1	Multifunction I/O	Yes	P0MAT.1 INT0.1 INT1.1 CLU0B.8 CLU2A.9 CLU3B.9	ADC0.0 CMP0P.0 CMP0N.0 AGND

6.4 EFM8LB1x-QSOP24 Pin Definitions

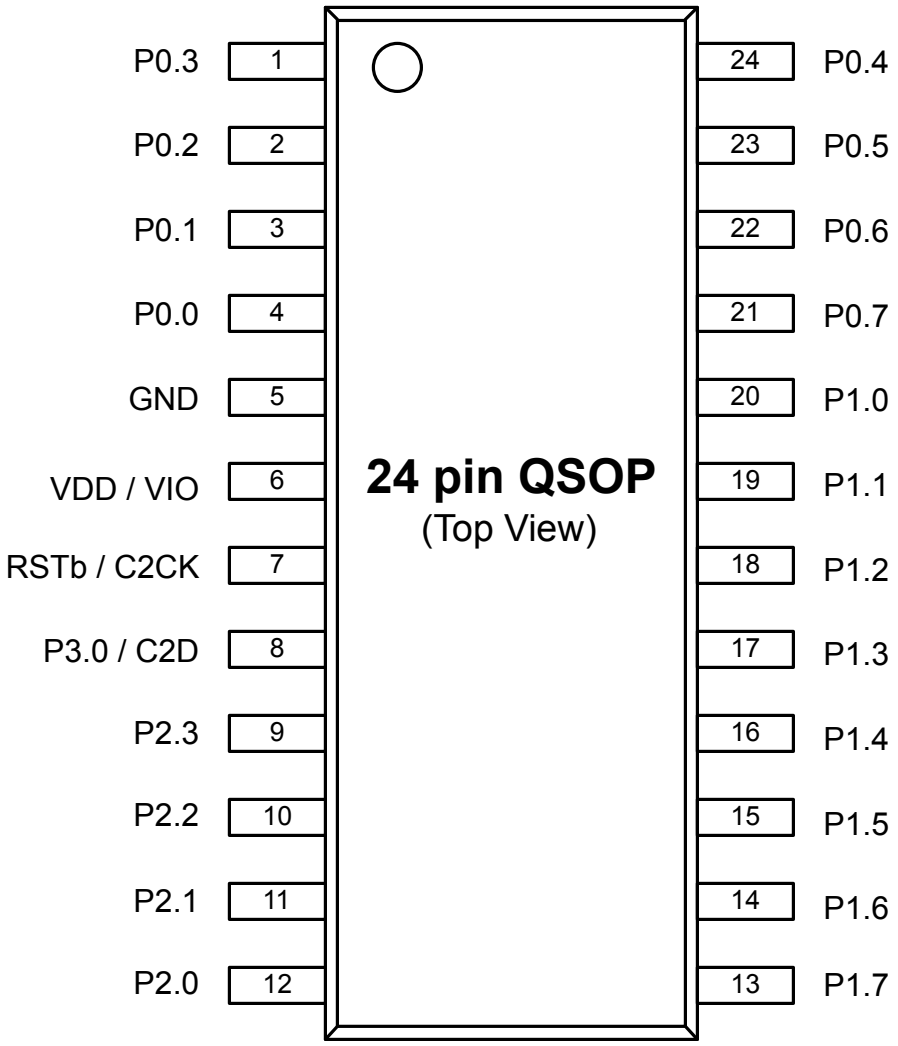

Figure 6.4. EFM8LB1x-QSOP24 Pinout

Table 6.4. Pin Definitions for EFM8LB1x-QSOP24

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
1	P0.3	Multifunction I/O	Yes	P0MAT.3 EXTCLK INT0.3 INT1.3 CLU0B.9 CLU2B.10 CLU3A.9	XTAL2

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
2	P0.2	Multifunction I/O	Yes	P0MAT.2 INT0.2 INT1.2 CLU0OUT CLU0A.9 CLU2B.8 CLU3A.8	XTAL1 ADC0.1 CMP0P.1 CMP0N.1
3	P0.1	Multifunction I/O	Yes	P0MAT.1 INT0.1 INT1.1 CLU0B.8 CLU2A.9 CLU3B.9	ADC0.0 CMP0P.0 CMP0N.0 AGND
4	P0.0	Multifunction I/O	Yes	P0MAT.0 INT0.0 INT1.0 CLU0A.8 CLU2A.8 CLU3B.8	VREF
5	GND	Ground			
6	VDD / VIO	Supply Power Input			
7	RSTb / C2CK	Active-low Reset / C2 Debug Clock			
8	P3.0 / C2D	Multifunction I/O / C2 Debug Data			
9	P2.3	Multifunction I/O	Yes	P2MAT.3 CLU1B.15 CLU2B.15 CLU3A.15	DAC3
10	P2.2	Multifunction I/O	Yes	P2MAT.2 CLU1A.15 CLU2B.14 CLU3A.14	DAC2

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
11	P2.1	Multifunction I/O	Yes	P2MAT.1 CLU1B.14 CLU2A.15 CLU3B.15	DAC1
12	P2.0	Multifunction I/O	Yes	P2MAT.0 CLU1A.14 CLU2A.14 CLU3B.14	DAC0
13	P1.7	Multifunction I/O	Yes	P1MAT.7 CLU0B.15 CLU1B.13 CLU2A.13	ADC0.12 CMP1P.6 CMP1N.6
14	P1.6	Multifunction I/O	Yes	P1MAT.6 CLU3OUT CLU0A.15 CLU1B.12 CLU2A.12	ADC0.11 CMP1P.5 CMP1N.5
15	P1.5	Multifunction I/O	Yes	P1MAT.5 CLU2OUT CLU0B.14 CLU1A.13 CLU2B.13 CLU3B.11	ADC0.10 CMP1P.4 CMP1N.4
16	P1.4	Multifunction I/O	Yes	P1MAT.4 I2C0_SCL CLU0A.14 CLU1A.12 CLU2B.12 CLU3B.10	ADC0.9 CMP1P.3 CMP1N.3
17	P1.3	Multifunction I/O	Yes	P1MAT.3 I2C0_SDA CLU0B.13 CLU1B.11 CLU2B.11 CLU3A.13	CMP1P.2 CMP1N.2

Dimension	Min	Typ	Max

Note:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.
3. This drawing conforms to JEDEC Solid State Outline MO-220.
4. Recommended card reflow profile is per the JEDEC/IPC J-STD-020C specification for Small Body Components.

7.2 QFN32 PCB Land Pattern

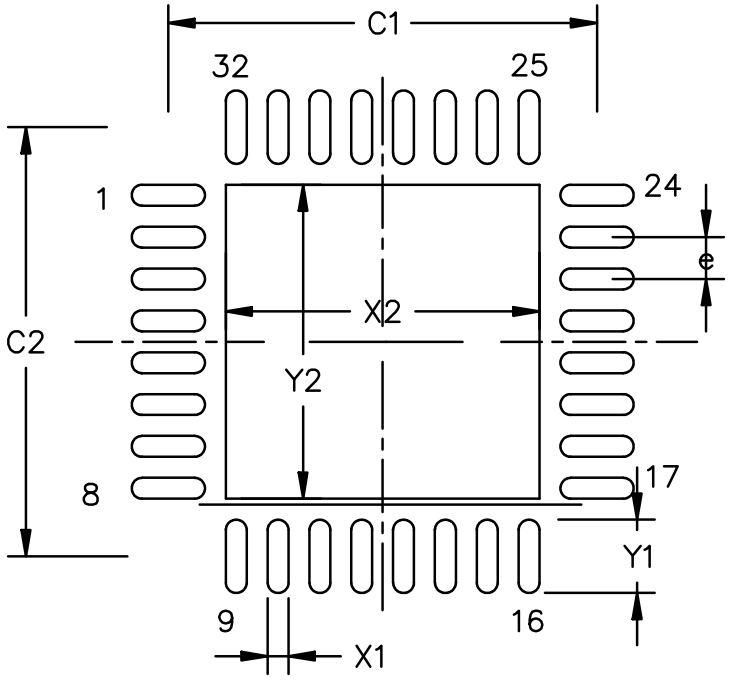

Figure 7.2. QFN32 PCB Land Pattern Drawing

Table 7.2. QFN32 PCB Land Pattern Dimensions

Dimension	Min	Max
C1	—	4.00
C2	—	4.00
X1	—	0.2
X2	—	2.8
Y1	—	0.75
Y2	—	2.8
e	—	0.4

Dimension	Min	Max

Note:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing is per the ANSI Y14.5M-1994 specification.
3. This Land Pattern Design is based on the IPC-7351 guidelines.
4. All dimensions shown are at Maximum Material Condition (MMC). Least Material Condition (LMC) is calculated based on a Fabrication Allowance of 0.05mm.
5. All metal pads are to be non-solder mask defined (NSMD). Clearance between the solder mask and the metal pad is to be 60 µm minimum, all the way around the pad.
6. A stainless steel, laser-cut and electro-polished stencil with trapezoidal walls should be used to assure good solder paste release.
7. The stencil thickness should be 0.125 mm (5 mils).
8. The ratio of stencil aperture to land pad size should be 1:1 for all perimeter pads.
9. A 2 x 2 array of 1.10 mm square openings on a 1.30 mm pitch should be used for the center pad.
10. A No-Clean, Type-3 solder paste is recommended.
11. The recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

7.3 QFN32 Package Marking

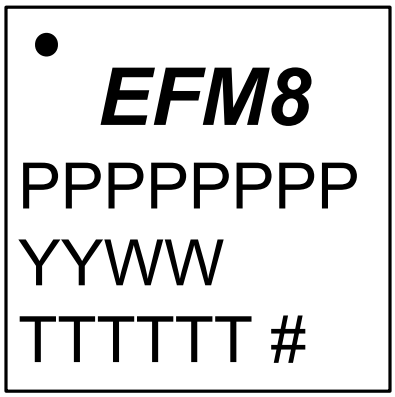

Figure 7.3. QFN32 Package Marking

The package marking consists of:

- PPPPPPPP – The part number designation.
- TTTTTT – A trace or manufacturing code.
- YY – The last 2 digits of the assembly year.
- WW – The 2-digit workweek when the device was assembled.
- # – The device revision (A, B, etc.).

9. QFN24 Package Specifications

9.1 QFN24 Package Dimensions

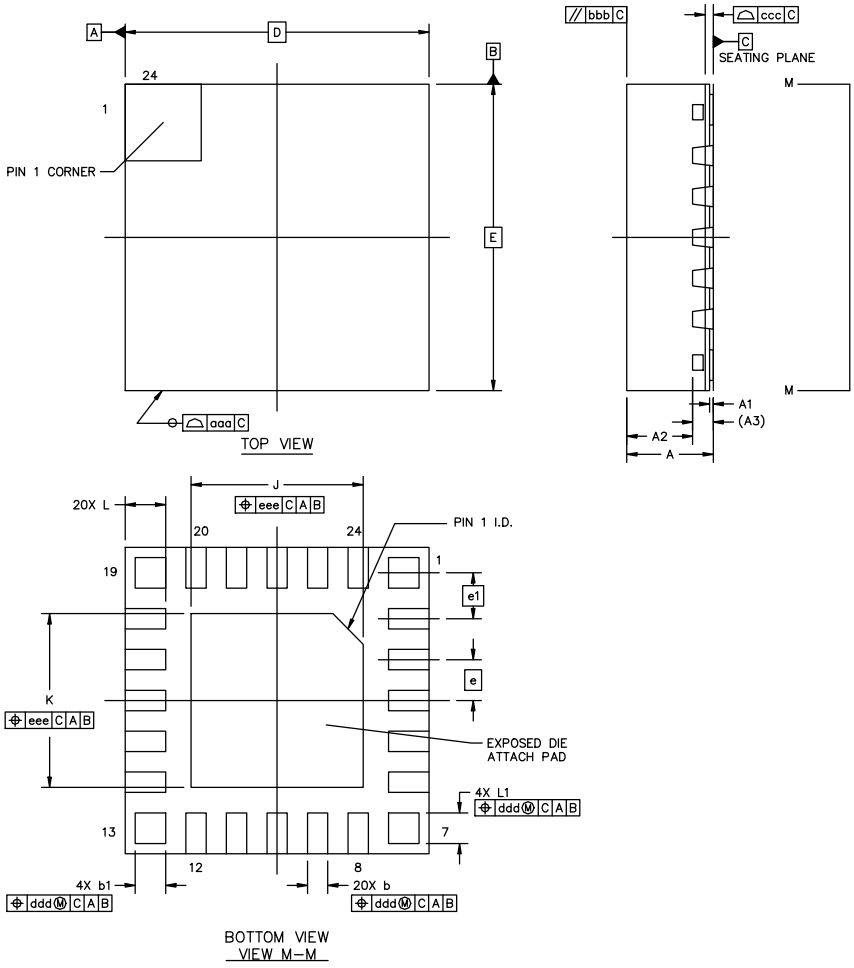

Figure 9.1. QFN24 Package Drawing

Table 9.1. QFN24 Package Dimensions

Dimension	Min	Typ	Max
A	0.8	0.85	0.9
A1	0.00	—	0.05
A2	—	0.65	—
A3		0.203 REF	
b	0.15	0.2	0.25
b1	0.25	0.3	0.35
D		3.00 BSC	
E		3.00 BSC	

Dimension	Min	Typ	Max
e		0.40 BSC	
e1		0.45 BSC	
J	1.60	1.70	1.80
K	1.60	1.70	1.80
L	0.35	0.40	0.45
L1	0.25	0.30	0.35
aaa	—	0.10	—
bbb	—	0.10	—
ccc	—	0.08	—
ddd	—	0.1	—
eee	—	0.1	—

Note:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.
3. This drawing conforms to JEDEC Solid State Outline MO-248 but includes custom features which are toleranced per supplier designation.
4. Recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

Dimension	Min	Typ	Max
aaa		0.20	
bbb		0.18	
ccc		0.10	
ddd		0.10	

Note:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.
3. This drawing conforms to JEDEC outline MO-137, variation AE.
4. Recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

10.3 QSOP24 Package Marking

Figure 10.3. QSOP24 Package Marking

The package marking consists of:

- PPPPPPPP – The part number designation.
- TTTTTT – A trace or manufacturing code.
- YY – The last 2 digits of the assembly year.
- WW – The 2-digit workweek when the device was assembled.
- # – The device revision (A, B, etc.).